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Renesas Technology Corp. Customer Support Dept. April 1, 2003



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Silicon N Channel MOS FET High Speed Power Switching

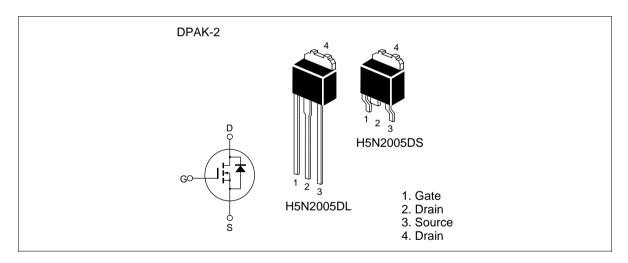


ADE-208-1373 (Z) Target Specification 1st. Edition Mar. 2001

Features

- Low on-resistance
- Low drive current
- High speed switching

Outline



Absolute Maximum Ratings (Ta = 25° C)

V _{DSS}			
V DSS	200	V	
V _{GSS}	±30	V	
I _D	(6)	А	
Note 1	(24)	А	
I _{DR}	(6)	А	
Note 1 DR (pulse)	(24)	А	
Pch Note 2	25	W	
θ ch-c	5	°C/W	
Tch	150	٥°C	
Tstg	-55 to +150	۵°	
	I _D Note 1 I _D (pulse) Note 1 I _{DR} Note 1 Pch Note 2 θ ch-c Tch Tch	$\begin{array}{c c} I_{D} & (6) \\ \hline I_{D \ (pulse)}^{Note 1} & (24) \\ \hline I_{DR} & (6) \\ \hline I_{DR} & (24) \\ \hline I_{DR \ (pulse)}^{Note 1} & (24) \\ \hline Pch^{Note 2} & 25 \\ \hline \theta \ ch-c & 5 \\ \hline Tch & 150 \\ \hline Tstg & -55 \ to +150 \\ \hline \end{array}$	I or coss Let of the second seco

Notes: 1. PW \leq 10 $\mu s,$ duty cycle \leq 1%

2. Value at Tc = $25^{\circ}C$

Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain to source breakdown voltage	$V_{(\text{BR})\text{DSS}}$	200			V	$I_{\rm D} = 10$ mA, $V_{\rm GS} = 0$
Gate to source leak current	I _{GSS}		_	±0.1	μA	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I _{DSS}		_	1	μA	$V_{\rm DS} = 200 \ V, \ V_{\rm GS} = 0$
Gate to source cutoff voltage	$V_{GS(off)}$	(3.0)	_	(4.5)	V	$V_{\rm DS} = 10 \text{ V}, \text{ I}_{\rm D} = 1 \text{ mA}$
Static drain to source on state resistance	$R_{\text{DS(on)}}$	—	(0.52)	(0.65)	Ω	$I_{\rm D}$ = 3 A, $V_{\rm GS}$ = 10 V ^{Note of}
Forward transfer admittance	y _{fs}	(2.0)	(3.4)	_	S	$I_{\rm D} = 3$ A, $V_{\rm DS} = 10$ V ^{Note 4}
Input capacitance	Ciss	_	(300)	_	pF	V _{DS} = 25 V
Output capacitance	Coss		(50)	_	pF	$V_{GS} = 0$
Reverse transfer capacitance	Crss	_	(14)	_	pF	f = 1 MHz
Total Gate charge	Qg	_	(9.5)	_	nC	V _{DD} = 160 V
Gate to source charge	Qgs		(1.8)	_	nC	V _{GS} = 10 V
Gateto drain charge	Qgd		(5.2)	_	nC	$I_{D} = 6 A$
Turn-on delay time	td(on)		(19)	_	ns	I _D = 3 A
Rise time	tr		(16)	—	ns	V _{GS} = 10 V
Turn-off delay time	td(off)		(44)	_	ns	$R_L = 33.3 \Omega$
Fall time	tf		(12)	_	ns	Rg = 10 Ω
Body-drain diode forward voltage	V_{DF}	—	(1.0)	(1.5)	V	$I_{F} = 6 A, V_{GS} = 0$
Body-drain diode reverse recovery time	trr	—	(90)	—	ns	$I_{F} = 6 A, V_{GS} = 0$
Body-drain diode reverse recovery charge	Qrr	—	(300)	—	nC	diF/dt = 100 A/us
Note: 4 Pulse test						

Electrical Characteristics (Ta = 25°C)

Note: 4. Pulse test

Package Dimensions

